

# VFTA010R045NA

**Datasheet** 



#### VFTA010R045NA

## **General Description**

V <sub>(BR)DSS</sub>	R <sub>DS(ON)_max</sub>	$I_D$
100V	4.5mΩ@10V	130A

## **Symbol**

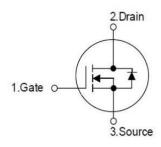


Figure 1 Symbol of VFTA010R045NA

#### **Features**

- $\blacksquare$  Low  $R_{DS(ON)}$
- Fast Switching and High efficiency
- 100% Avalanche Tested
- RoHS compliant

## **Application**

- PD charger
- Motor driver
- Switching voltage regulator
- DC-DC converter
- Switched mode power supply

## Package Type



Figure 2 Package Type of VFTA010R045NA

## **Ordering Information**

Product Name	Package			
VFTA010R045NA	TO-220			



### VFTA010R045NA

## Absolute Maximum Ratings (TA= 25 °C, unless otherwise specified)

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage		$ m V_{DSS}$	100	V
Gate-Source Voltage		$ m V_{GSS}$	±20	V
Continuous Drain Current (Silicon Limited)	$T_C=25^{\circ}C$		170	
Continuous Drain Current (Wire Bond Limited)	$T_C=25$ °C	$I_D$	130	A
Continuous Drain Current (Silicon Limited)	T <sub>C</sub> =100°C		120	
Pulsed Drain Current Note 1	T <sub>C</sub> =25°C	I <sub>D.pulse</sub>	675	A
Continuous Diode Forward Current	T <sub>C</sub> =25°C	Is	130	A
Continuous Drain Current	T <sub>A</sub> =25°C	I	16	A
Continuous Drain Current	T <sub>A</sub> =70°C	$I_{ m DSM}$	12	A
Max Power Dissipation Note 3	$T_{\rm C}=25^{\rm o}{\rm C}$	P <sub>D</sub>	250	W
Max Power Dissipation Note 4	$T_A=25^{\circ}C$	P <sub>DSM</sub>	2.1	W
Avalanche Energy, Single Pulse Note 2		Eas	484	mJ
Operation and storage temperature		T <sub>J</sub> ,T <sub>STG</sub>	-55 to 175	°C

## **Thermal Resistance**

Parameter	Symbol	Min	Тур	Max	Unit
Thermal Resistance, Junction-to-Case Note 5	$R_{ heta JC}$		0.5	0.6	°C/W
Thermal Resistance, Junction-to-Ambient Note 6	$R_{ heta JA}$		50	60	C/W





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### Electrical Characteristics(T<sub>J</sub>= 25 °C, unless otherwise specified)

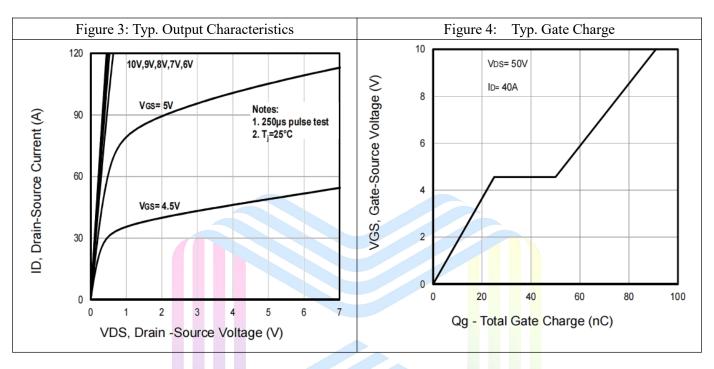
	Parameter		Symbol	<b>Test Conditions</b>	Min	Тур	Max	Unit	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Statistic Characteristics								
	Drain-Source Breakdown Voltage		BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	100			V	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Zero Gate Voltage Drain Current		T.	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V			1	uA	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Zero Gate Voltage Drain Curren	t T <sub>J</sub> = 125 °C	IDSS	V <sub>DS</sub> =100V, V <sub>GS</sub> =0V			100	uA	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate-Body Leakage Current	Forward	$I_{GSSF}$	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V			100	nA	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$		Reverse	I <sub>GSSR</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V			-100		
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate Threshold Voltage		V <sub>GS(TH)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	2.2	2.7	3.2	V	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Drain-Source On-Resistance <sup>Note7</sup>		D	V <sub>GS</sub> =10V, I <sub>D</sub> =40A		3.6	4.5	mΩ	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Drain-Source On-Resistance <sup>Note7</sup> T <sub>J</sub> = 100 °C		KDS(ON)			4.7			
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate resistance		$R_G$	f=1 MHz, Open drain		1.8		Ω	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Dynamic Characteristics								
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Input Capacitance		C <sub>ISS</sub>	V <sub>DS</sub> =50V		5440		pF	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Output Capacitance		Coss	V <sub>GS</sub> =0V		1035		pF	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Reverse Transfer Capacitance		C <sub>RSS</sub>	f=1MHz		35		pF	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Turn-on Delay Time		t <sub>d(on)</sub>	$V_{DS}=50V$		21			
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Rise Time		t <sub>r</sub>	I <sub>D</sub> =40A	69			]	
	Turn-off Delay Time		$t_{ m d(off)}$	$R_G=3\Omega$		57		ns	
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Fall Time		$t_{\rm f}$	V <sub>GS</sub> =10V		70			
	<b>Gate Charge Characteristics</b>								
	Gate to Source Charge		$Q_{gs}$	V <sub>GS</sub> =10V		25			
	Gate to Drain Charge		$Q_{\mathrm{gd}}$	$V_{DS}=50V$		25		nC	
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	Gate Charge Total@V <sub>GS</sub> =10V		Qg	$I_D=40A$		91			
Reverse Recovery Time $t_{rr}$ $I_{SD}=40 A V_{GS}=0 V$ 59 ns	Reverse Diode Characteristics	<u> </u>	•						
	Drain-Source Diode Forward Voltage		$V_{\mathrm{SD}}$	V <sub>GS</sub> =0V, I <sub>SD</sub> =40A		0.8	1.2	V	
Reverse Recovery Charge Q <sub>rr</sub> di/dt=100A/us 71 nC	Reverse Recovery Time		t <sub>rr</sub>	I <sub>SD</sub> =40A V <sub>GS</sub> =0V		59		ns	
	Reverse Recovery Charge	ΛΓ	Qrr	di/dt=100A/us		71		nC	

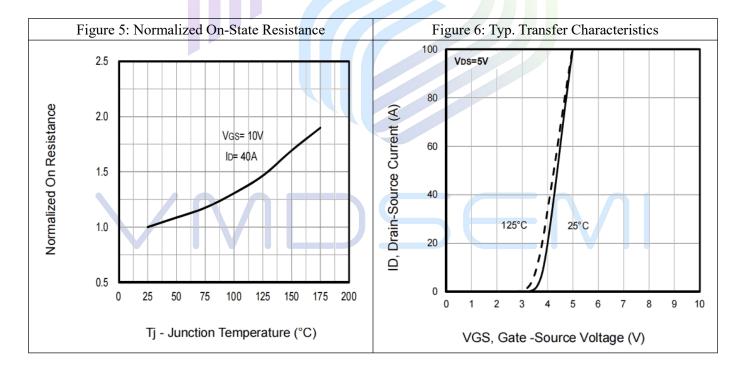
#### Notes:

- 1. Single pulse; pulse width  $\leq 100 \mu s$ .
- 2. EAS of 484mJ is based on starting  $T_J$  = 25°C, L = 0.5mH,  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = 44A,  $V_{GS}$  =10V;100% FT tested at L = 0.5mH,  $I_{AS}$  = 22A.

- 3. The power dissipation Pd is based on Ti(max), using junction-to-case thermal resistance  $R_{\theta JC}$ .
- 4. The power dissipation Pdsm is based on Tj(max), using junction-to-ambient thermal resistance  $R_{\theta JA}$ .
- 5. Thermal resistance from junction to soldering point (on the exposed drain pad). These tests are performed on a cool plate.
- 6. The value of  $R_{\theta JA}$  is measured with the device in a still air environment with  $T_A = 25$ °C.
- 7. Pulse width  $\leq 380 \mu s$ ; duty cycle  $\leq 2\%$ .

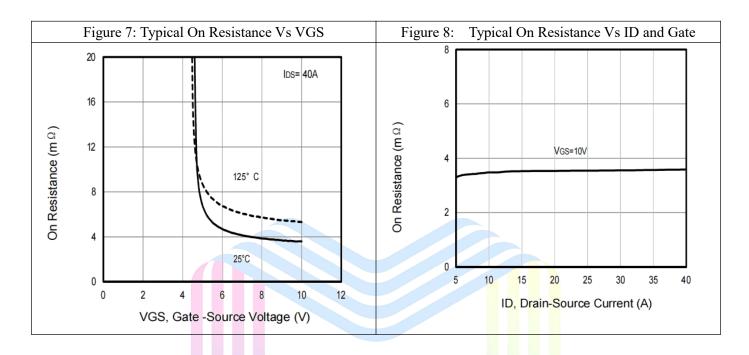
## **Typical Performance Characteristics**

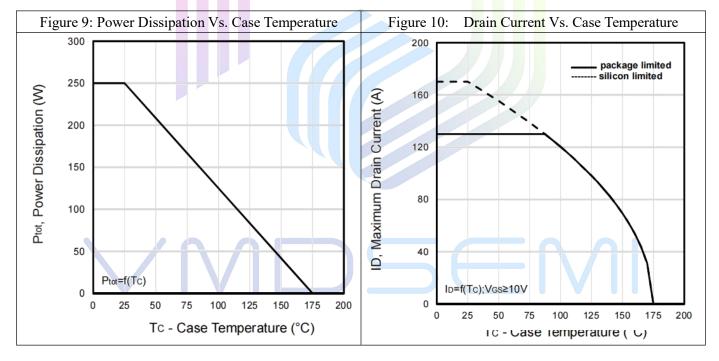






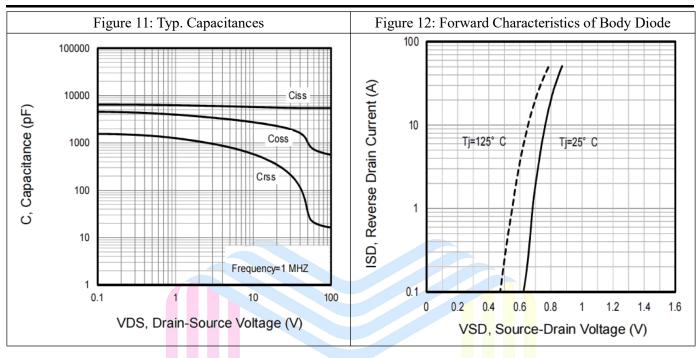
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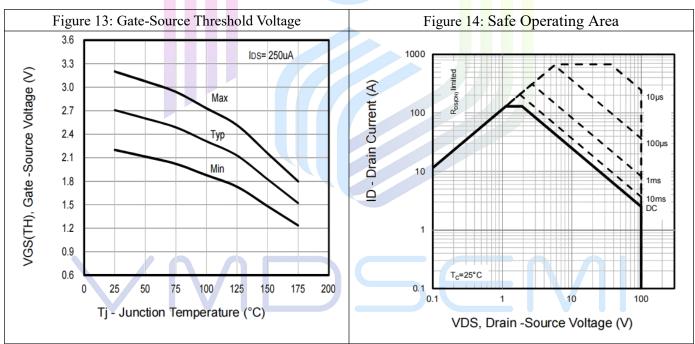






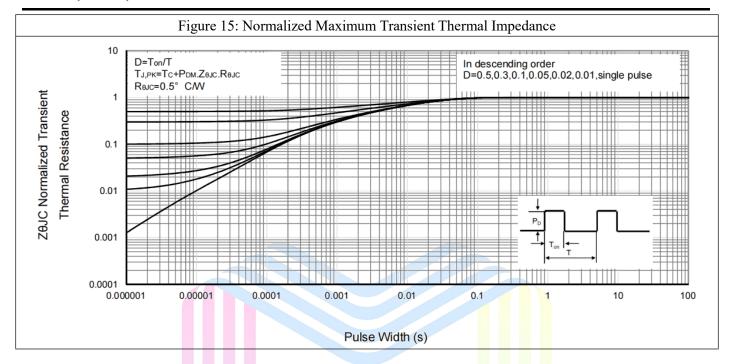
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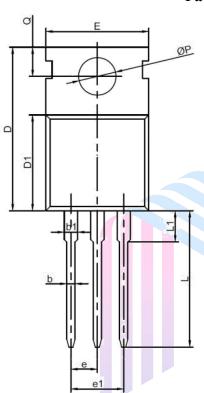


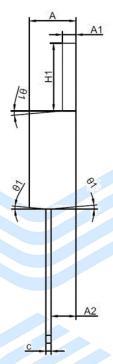


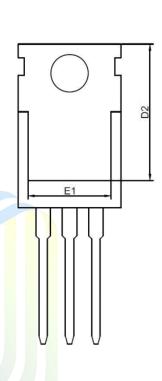


### **Mechanical Dimensions**

### **Package Information TO-220**







Symbol	Dimensions (unit: mm)				
Syllibol	Min	Тур	Max		
Α	4.30	4.52	4.70		
A1	1.15	1.30	1.40		
A2	2.20	2.40	2.60		
b	0.70	0.80	1.00		
b1	1.15	1.32	1.50		
С	0.45	0.50	0.65		
D	15.10	15.70	16.10		
D1	8.80	9.20	9.40		
D2	12.80	-	13.70		
E	9.65	9.90	10.30		
E1	7.00	-	8.2		
е	2.54 BSC				
e1		5.08 BSC			
H1	6.20	6.50	6.90		
L	12.70	-	13.90		
L1	-	-	3.50		
ΦP	3.40	3.60	3.80		
Q	2.60	2.80	3.00		
θ1	1 °	3 °	7 °		

#### Notes:

- 1. Refer to JEDEC TO-220 variation AB
- Dimension "D" and "E" do NOT include mold flash.Mold flash shall not exceed 0.127mm per side.



VFTA010R045NA

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